

Seat No.: _____

Enrolment No. _____

GUJARAT TECHNOLOGICAL UNIVERSITY
BE - SEMESTER-VIII • EXAMINATION – WINTER • 2014

Subject Code: 180802

Date: 29-11-2014

Subject Name: VLSI Technologies

Time: 02:30 pm - 05:00 pm

Total Marks: 70

Instructions:

1. Attempt all questions.
2. Make suitable assumptions wherever necessary.
3. Figures to the right indicate full marks.

- Q-1** (a) Discuss VLSI design flow in brief. (Y – chart) 7
(b) Explain design procedure steps for fabrications of n-MOS transistor. 7
- Q-2** (a) Explain Channel Length Modulation. 7
(b) Explain energy band diagram of MOS structure at surface inversion and derive the equation of threshold voltage. 7
- OR
- Q-2** (b) Explain major types of capacitances and show its variation under different operating regions and physical parameters. 7
- Q-3** (a) Draw the CMOS Inverter circuit and VTC for different operation regions of the nMOS and pMOS transistor. Derive critical voltage points V_{OH} , V_{OL} , V_{IL} and V_{IH} . 7
(b) Discuss basic steps of the LOCOS Process. 7
- OR
- Q-3** (a) Derive the expression for drain current as a function of V_{GS} , V_{DS} and V_{SB} for all three region of operation of MOSFET using Gradual Channel Approximation. 7
(b) Explain two different down scaling techniques for MOSFET. Which technique is preferable? 7
- Q-4** (a) Explain the functioning of depletion load nMOS inverter and derive critical voltage points V_{OH} , V_{OL} , V_{IL} and V_{IH} . 7
(b) Concept of regularity, modularity and locality. 7
- OR
- Q-4** (a) Explain delay time definitions for MOS Inverters Switching Characteristics and derive the Expression for λ_{PHL} & λ_{PLH} 7
(b) Writes a short note on Design Quality. 7
- Q-5** (a) Discuss Complementary pass transistor logic. Realize the XOR gate using CPL 7
(b) Explain the criteria to measure the design quality to improve the chip design and explain any two in brief 7
- OR
- Q-5** (a) List the important concern for the IC packaging technology. Also Explain different packaging technologies. 7
(b) Write a short note on Built In Self Test (BIST). 7
